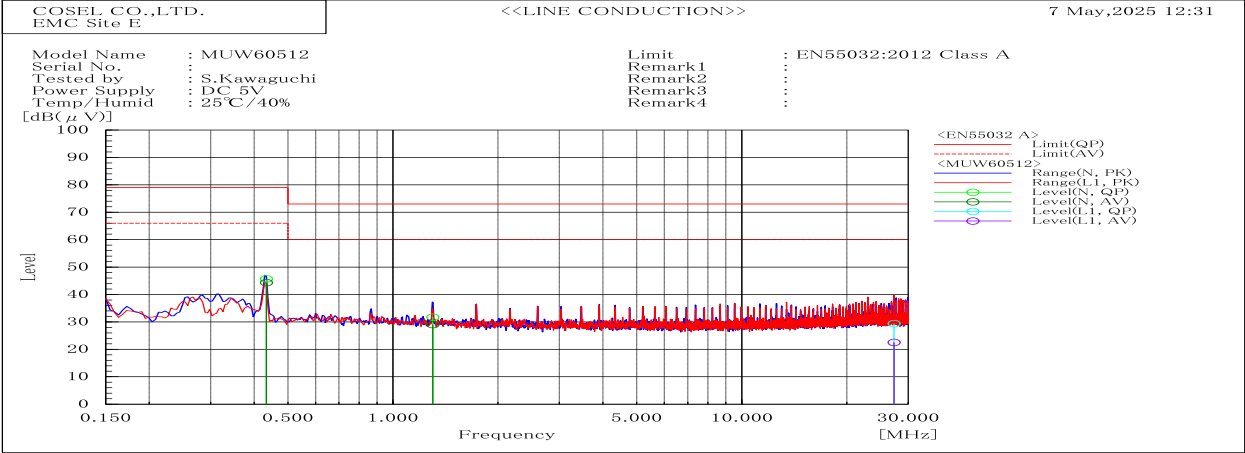
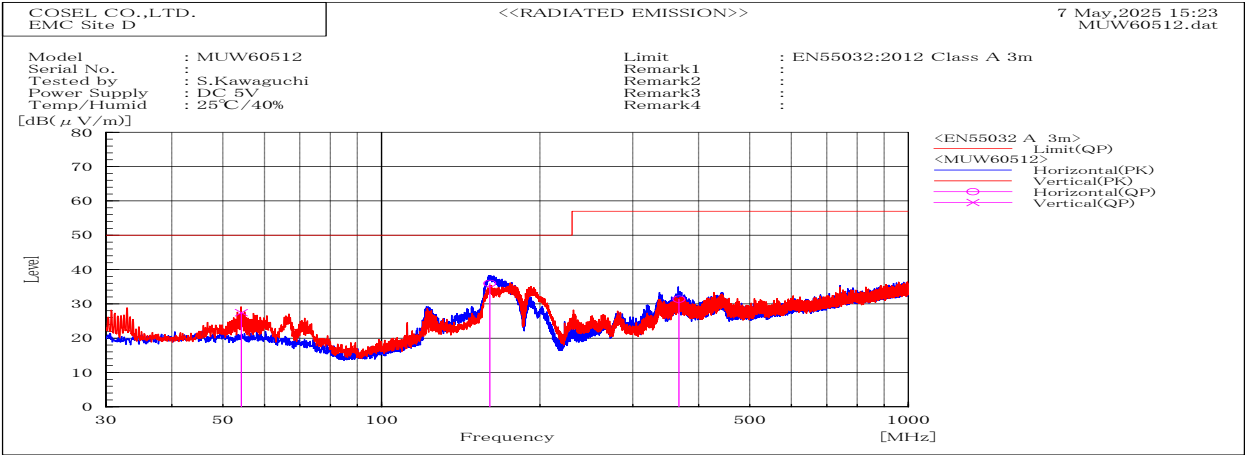


DATA SHEET		Date	07-May-25
Model	MUW60512	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi



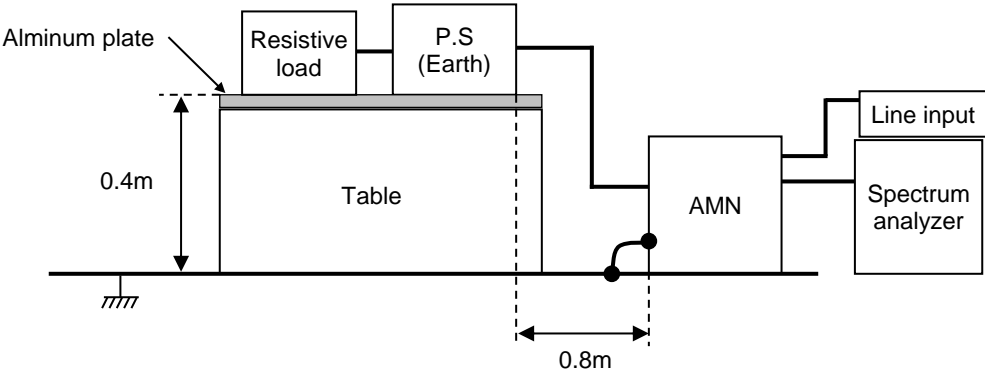
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.433	N	45.7	44.4	79	66	33.3	21.6	Pass	
1.301	N	31.8	29	73	60	41.2	31	Pass	
27.331	L1	29.4	22.5	73	60	43.6	37.5	Pass	



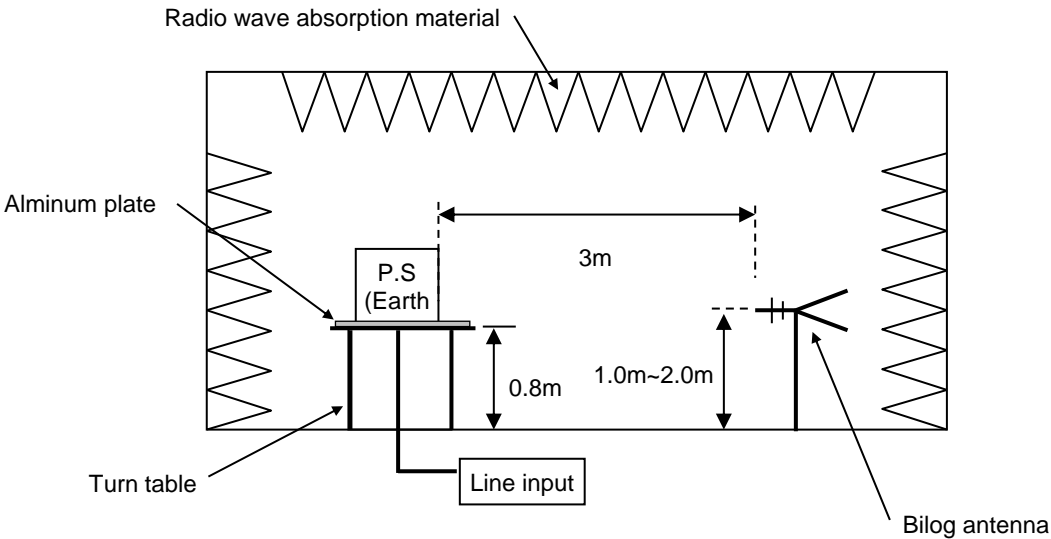
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(uV/m) QP	dB(uV/m) QP	dB QP				
160.514	H	Stable	35.9	50	14.1	Pass	185.6	46.6	
54.211	V	Stable	27.5	50	22.5	Pass	100	289.2	
366.913	H	Stable	31.4	57	25.6	Pass	100.3	87.6	

DATA SHEET		Date	07-May-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission

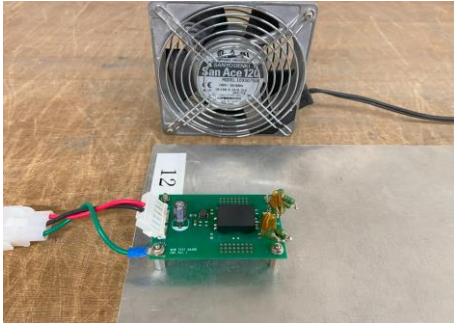


Conditions

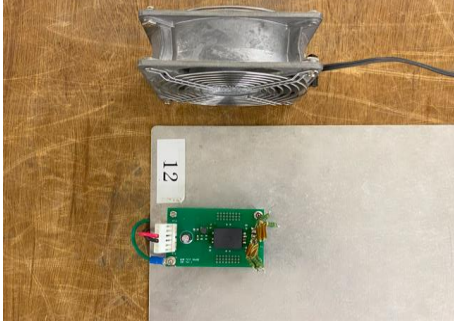
Test : EMI
Model Name: MUW6□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

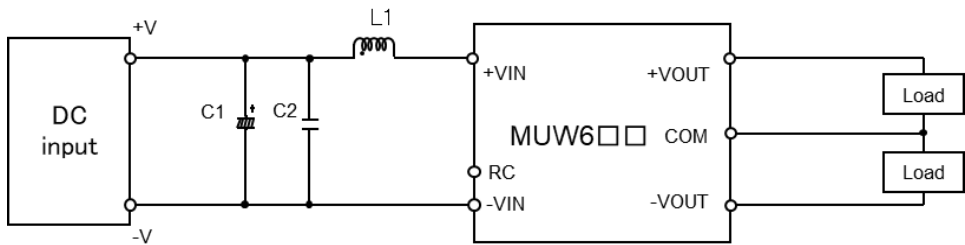


Fig.1 MUW6□□ Testing circuitry

C1 :	MUW605□	16V 220 μ F	Electric capacitor (UPWseries NICHICON)
	MUW612□	50V 100 μ F	Electric capacitor (UPWseries NICHICON)
	MUW624□	—	
	MUW648□	—	
C2 :	MUW605□	16V 22 μ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUW612□	25V 10 μ F	Ceramic capacitor (CM316X7R106K25AT KYOCERA)
	MUW624□	50V 4.7 μ F	Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUW648□	100V 2.2 μ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUW605□	6500mA 1.5 μ H	Inductor(LQH5BPN1R5N38 MURATA MANUFACTURING)
	MUW612□	5000mA 2.2 μ H	Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING)
	MUW624□	2600mA 10 μ H	Inductor(LQH5BPN100M38 MURATA MANUFACTURING)
	MUW648□	1600mA 22 μ H	Inductor(LQH5BPN220M38 MURATA MANUFACTURING)